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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE 27 JUL 2006

Appl. No.

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Confirmation No.

Unassigned

Applicant

Andrea Scarpa et al.

Filed

Concurrently

TC/A.U. Examiner Unassigned-Unassigned

Docket No.

NL04 0019US1

Customer No.

24738

Title:

Method and Apparatus for Testing Integrated Circuits for

Susceptibility to Latch-Up

**Commissioner for Patents** 

P.O. Box 1450

Alexandria, VA 22313-1450

## PRELIMINARY AMENDMENT

Sir:

Prior to calculation of the filing fee and examination please amend the aboveidentified application as follows:

Amendments to the Specification begin on page 2 in this paper.

Amendments to the Claims begin on page 3 in this paper.

Remarks/Arguments begin on page 6 of this paper.